

Search Notes

Application/Control No.

10/619,623

Examiner

Tien Dinh

Applicant(s)/Patent under
Reexamination

YAMASHITA ET AL.

Art Unit

3644

SEARCHED

Class	Subclass	Date	Examiner
244	123	6/23/04	TD
416	232		
	233	6/23/04	TD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Ext Text Search	6/18/06	TD